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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Doug Larson et al.	)	Group Art Unit 2816
Serial No.	:	10/039,720	)	
Filed	:	December 31, 2001	)	
For	:	TIME SHIFT CIRCUIT FOR FUNCTIONAL AND AC PARAMETRIC TEST	)	
Examiner	:	Unknown	)	

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of  
Patents and Trademarks  
Washington, D.C. 20231

Dear Sir:

Pursuant to the duty of disclosure under 37 CFR 1.97, enclosed is a form PTO-1449 listing four references relevant to the above-identified application. A copy of each reference is also enclosed. This information disclosure statement is filed before the first office action on the merits under 37 CFR 1.97(b) (3). The prior art references enclosed herewith are:

- (1) U.S. Patent No. 6,263,463 entitled "Timing adjustment circuit for semiconductor test system".
- (2) U.S. Patent No. 6,058,057 entitled "Timing generator for semiconductor test system".
- (3) U.S. Patent No. 6,032,282 entitled "Timing edge forming circuit for IC test system".
- (4) U.S. Patent No. 6,058,057 entitled "Timing signal generation circuit for semiconductor test system".

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REMARKS

Applicant respectfully requests that the references disclosed in the statement be considered in the substantive examination of this case.

Respectfully submitted,

MURAMATSU & ASSOCIATES

Dated: 4/18/2002

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